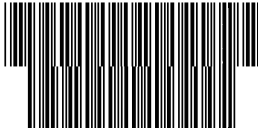


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>1069252511556612</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>TANGEN ET AL.ZHOU ET AL.</p>
	<p>Examiner</p> <p>Quoc, Tran AQuoc A. Tran</p>	<p>Art Unit</p> <p>21762176</p>

SEARCHED			
Class	Subclass	Date	Examiner
715	234, 249	11/12/09	RSD
Above	Updated	06/06/10	RSD
Above	Updated	09/30/10	RSD
Above715	Updated513	11/1/20101/9/2007	QTQT
703	22	1/9/2007	QT
707	1-2	9/11/2007	QT
UPDATED	ABOVE	9/4/2007	QT
UPDATED	UPDATED	1/4/2008	QT
Updated	Updated	8/3/2008	QT
Updated	Updated	12/10/2008	QT
Updated	Updated	6/20/2009	QT
Updated	Updated	12/20/2009	QT
Updated	Updated	11/4/2010	QT

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM-TDB)ecN	11/12/09	RSD	
Google Scholar	11/12/09	RSD	
EAST Search Updated	06/06/10	RSD	
EAST Search Updated - Search Notes Attached	09/30/10	RSD	
UpdatedEAST (USPAT, USPGPUB, JPO, USOCR, FPRS, EPO, DERWENT & IBM_TDB)	11/1/20101/9/2007	QTQT	
The ACM Digital Library "XBRL"	1-10-2007	QT	
UPDATED ABOVE	9/4/2007	QT	
UPDATED ABOVE	1/4/2008	QT	
Inventors Searched Conducted- Considered Double Patent Rejection	1/4/2008	QT	
Updated	8/3/2008	QT	
Updated	12/10/2008	QT	
Updated	6/20/2009	QT	
Updated	12/20/2009	QT	
Updated	11/4/2010	QT	

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Examiner.Art Unit 2176/QUOC A TRAN/
Examiner.Art Unit 2176

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
715	212	11/4/2010	QT
717	162	11/4/2010	QT
709	203	11/4/2010	QT
707	100	11/4/2010	QT

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Examiner.Art Unit 2176/QUOC A TRAN/
Examiner.Art Unit 2176